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X-Ray Diffraction and Physical Properties of Potassium Fullerides K_xC_{70}

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X-ray diffraction and magnetic-susceptibility measurements have been carried out for single phase K_xC_{70} ($x=1, 3, 4, 6$ and 9) compounds synthesized by heating stoichiometric amount of K_9C_{70} and C_{70} . The x-ray diffraction profiles show no structural transition down to 10K. The fairly large temperature-independent paramagnetic contribution was observed in $x=3$ and 4 . The electrical resistivity has been measured for K evaporated C_{70} film with increasing K thickness. Two resistivity minima were observed at $x=1$ and 4 .

Keywords: C_{70} ; fulleride; x-ray diffraction; magnetic susceptibility; resistivity

INTRODUCTION

Since the discovery of superconductivity in K_3C_{60} by Hebard et al.^[1], many attempts to dope a wide variety of atoms or molecules into fullerene have been made. As for K_xC_{70} , four doped phases, namely the fcc phase at $x=3$, the bct phase at $x=4$, the bcc phase at $x=6$ and the K-saturated fcc phase at $x=9$ were reported^[2]. Wang et al. reported metallic behavior of K_xC_{70} film with $x=4$ by using FIT model^[3]. Superconductivity in K_xC_{70} has not been reported except an appearance of a small diamagnetism in K_xC_{70} which resulted from C_{60} impurity by Imaeda et al.^[4] and doped rhombohedral phase by the present authors^[2].

In this paper, we report the x-ray diffraction and the magnetic-susceptibility measurements for K_xC_{70} ($x=1, 3, 4, 6$ and 9) together with the resistivity of K_xC_{70} film as a function of K concentration in order to search metallic phase.

EXPERIMENTS

The starting materials were sublimed C_{70} polycrystal(99% up purity, MER

Co.) and purified C_{70} powdered crystals extracted with toluene(99% purity, MER Co.). The toluene-extracted C_{70} was washed using THF(tetrahydrofuran) and heated at 300 °C for 6 h under a vacuum of the order of 10^{-1} Pa to remove the solvent. The fcc C_{70} was prepared by I_2 intercalation. After removing I_2 , the fcc C_{70} with $a=14.97$ Å was obtained^[5]. Figure 1 shows this process and the removal of I_2 was also checked by weight measurement.

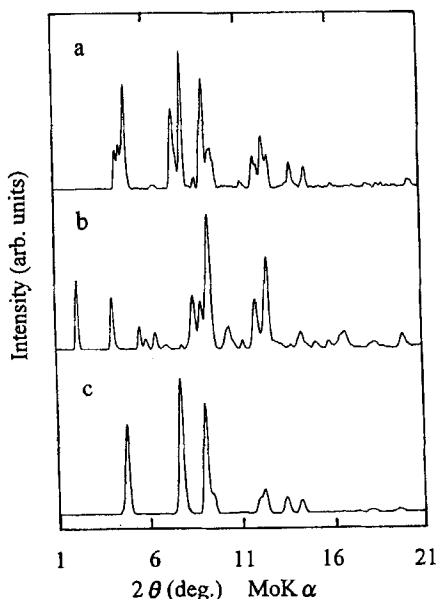


FIGURE 1 X-ray diffraction profiles for (a) sublimed C_{70} , (b) $C_{70}I_4$ and (c) fcc C_{70} (after I_2 de-intercalation).

Single-phase K_xC_{70} ($x=1, 3, 4, 6$ and 9) were synthesized by annealing stoichiometric amount of K_9C_{70} and C_{70} . For SQUID measurement, sample was transferred to a quartz tube with a partition in the center. For x-ray diffraction measurement, specimen was transferred to a capillary in a glove box.

The x-ray diffraction analysis was performed by a system equipped with an 18-kW rotating molybdenum anode as the x-ray generator and an imaging plate(IP, MAC Science, DIP100) as the detector. The synchrotron radiation(SR) at Photon Factory(KEK-PF, BL6C1 and BL1B) was also used. For resistivity measurement, about 1000 Å-thick C_{70} film was prepared on glass substrate at 150°C after evaporating four gold strips as contacts. Base pressure was 10^{-4} Pa. K metal was evaporated onto C_{70} film at 150°C and the resistance of the film was monitored continuously by means of four-terminal method. Composition was estimated from the thickness ratio of C_{70} to K. The temperature dependence measurement was performed in a liquid nitrogen reservoir. A SQUID magnetometer(Quantum Design, MPMS-5SH) was used

for magnetic-susceptibility measurements.

RESULTS AND DISCUSSIONS

The x-ray diffraction profiles at room temperature (RT) for K_xC_{70} ($x=1, 3, 4, 6$ and 9) from fcc C_{70} using MoK α radiation are shown in Fig. 2. K_1C_{70} and K_3C_{70} can be assigned to fcc structures with $a=14.84$ and 14.96 Å, respectively. K_4C_{70} can be assigned to a bct structure with $a=12.63$ Å and $c=10.95$ Å. K_6C_{70} has a bcc structure with $a=12.00$ Å. The K-saturated phase K_9C_{70} has an fcc structure with $a=15.67$ Å.

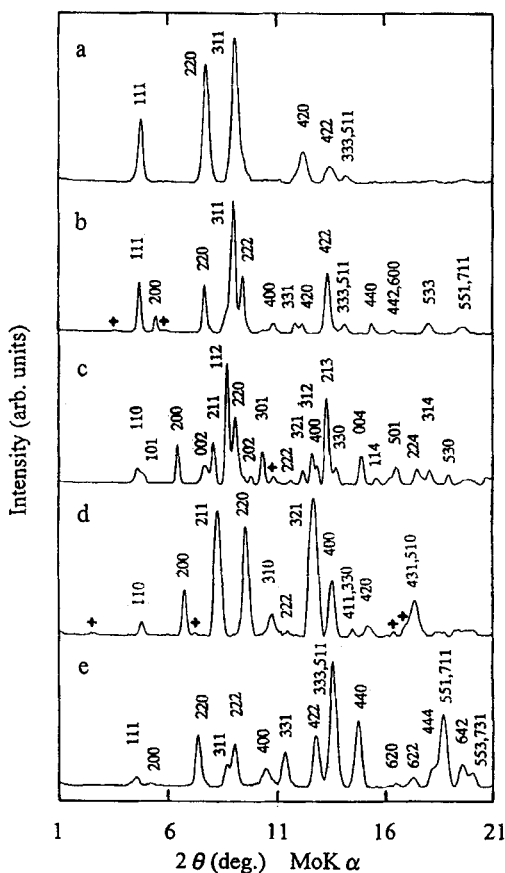


FIGURE 2 X-ray diffraction profile for K_xC_{70} : (a) $x=1$, (b) $x=3$, (c) $x=4$, (d) $x=6$ and (e) $x=9$. + symbols indicate unidentified peaks.

Figure 4 shows the electrical resistivity of K_xC_{70} film as a function of K concentration. It has two minima: 1.0×10^{-1} ohmcm at $x=1$ and 6.1×10^{-3} ohmcm at about $x=4$. The latter value is about the same order to that for K_3C_{60} film^[7]. The resistivity for $x=4$ film gradually increased with decreasing temperature down to 77K consistent with the result of Wang et al.^[3] The temperature dependence of the magnetic susceptibility χ for K_xC_{70} ($x=1, 3, 4, 6$ and 9) using a SQUID under ST is shown in Fig.5.

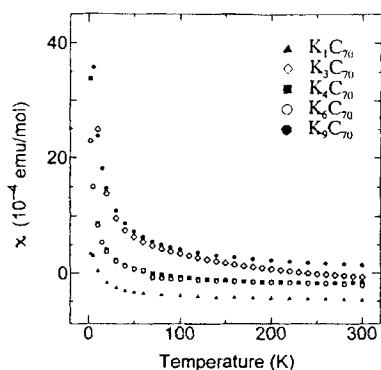


FIGURE 5 Temperature dependence of the magnetic susceptibility for K_xC_{70} ($x=1, 3, 4, 6$ and 9).

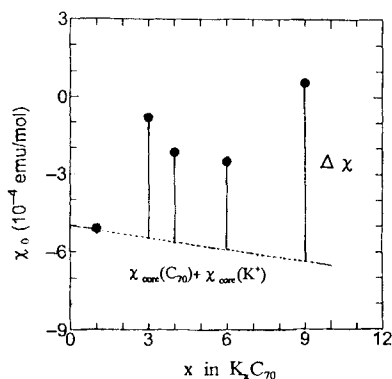


FIGURE 6 K concentration dependence of the temperature-independent magnetic susceptibility χ_0 . Solid circles show χ_0 . The dotted line shows the contribution from $\{\chi_{core}(C_{70}) + x \times \chi_{core}(K^*)\}$.

The temperature-independent term χ_0 was obtained by fitting the results to the formula $\chi = C/(T - \theta) + \chi_0$, where C is the Curie constant and θ is the Weiss

temperature. The χ_0 values for K_1C_{70} , K_3C_{70} , K_4C_{70} , K_6C_{70} and K_9C_{70} are estimated to be -5.10, -0.80, -2.15, -2.50 and 0.57 (in $\times 10^{-4}$ emu/mol units), respectively, and depicted in Fig.6. The magnetic susceptibility shift $\Delta\chi$ for K_xC_{70} defines as $\Delta\chi = \chi_0 - \{\chi_{\text{core}}(C_{70}) + x \times \chi_{\text{core}}(K^*)\}$, where the $\chi_{\text{core}}(C_{70})$ and $\chi_{\text{core}}(K^*)$ are the core contributions from C_{70} and K^* , respectively. $\Delta\chi$ for each x is shown by vertical solid line in Fig.6. Paramagnetic $\Delta\chi$ of 4.7×10^{-4} emu/mol and 3.5×10^{-4} emu/mol were obtained for $x=3$ and $x=4$ phases, respectively. These paramagnetic contributions may result from Pauli paramagnetism and show the metallic character for $x=3$ and 4 phases. The $x=6$ and $x=9$ phases also have fairly large paramagnetic $\Delta\chi$. The core contributions for these two phases should be re-estimated because of the participation of t_{1g} -derived band. A small diamagnetism was observed in some samples with $x \approx 3$ below 0.5 K, but has highly sample dependence.

SUMMARY

K_xC_{70} has a structure sequence of the doped fcc($x=1$), the doped fcc($x=3$), the bct($x=4$), the bcc($x=6$) and the K-saturated fcc($x=9$) phases with increasing K concentration. The electrical resistivity of K_xC_{70} film shows two minima at $x=1$ and 4. The large temperature-independent paramagnetic contribution was observed in $x=3$ and 4. These results show the metallic character of $x=3$ and 4.

Acknowledgments

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